Report No.: GTSL202012000218

RF Exposure Evaluation

Applicant: Adam Elements International Co., LTD.

Address of Applicant: 10F.-3, No.54, Songjiang Rd., Zhongshan Dist., Taipei City,

Taiwan

Manufacturer/Factory: Shenzhen Jizhitai Technology Co.,Ltd

Address of 3/F Block 37 & 1/F Block 38 Baotian Industry, Chentian

Manufacturer/Factory: Community, Xixiang Street, Bao'an District, Shenzhen, China.

Equipment Under Test (EUT)

Product Name: Wireless Charging Cup Heater with adapter

Model No.: OMNIA Q Hot, APAADQHOTUSGY

Test sample(s) ID: GTS202012000218-1

Sample(s) Status Engineer sample

Modulation type: MSK

Antenna Type: Inductive loop coil Antenna

Antenna gain: 0dBi

Power supply: 5V,9V,12V

2A,1.67A,1.5A

15W

FCC ID: 2ABY9OMNIA-QHOT

Applicable standards: KDB 680106 D01 RF Exposure Wireless Charging Apps v03

Date of sample receipt: 2020-11-23

Date of Test: 2020-11-23~2020-12-15

Date of report issued: 2020-12-21



1 Measuring Standard

KDB 680106 D01 RF Exposure Wireless Charging Apps v03

2 Requirements

According to the item 5 of KDB 680106 D01v03:

Inductive wireless power transfer applications that meet all of the following requirements are excluded from submitting an RF exposure evaluation.

(1) Power transfer frequency is less than 1MHz.

The device operate in the frequency range 110KHz~205KHz.

(2) Output power from each primary coil is less than or equal to 15 watts.

The maximum output power for each primary coil is 15W.

(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.

The transfer system includes 1 primary coils.

(4) Client device is placed directly in contact with the transmitter.

Client device is placed directly in contact with the transmitter

- (5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion). Mobile exposure conditions only
- (6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.

The EUT H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.

Remark: Meet all the above requirements.

The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in 1.1307(b)

Limits for Maximum Permissible Exposure (MPE)

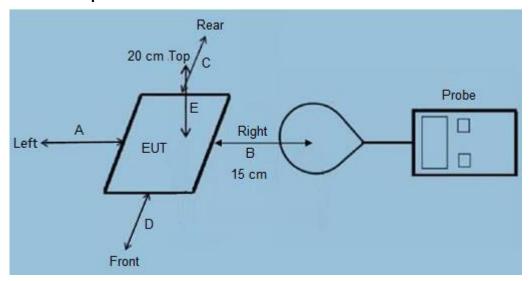
Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging tim (minutes)					
(A) Limits for Occupational/Controlled Exposures									
0.3-3.0	0.3-3.0 614 1.63 *(100)								
3.0-30	1842/f	4.89/f	*(900/f ²)	6					
30-300	61.4	0.163	1.0	6					
300-1500	/	/	f/300	6					
1500-100,000	1	/	5	6					
	(B) Limits for Genera	Population/Uncontrolle	d Exposure						
0.3-1.34	614	1.63	*(100)	30					
1.34-30	824/f	2.19/f	*(180/f ²)	30					
30-300	27.5	0.073	0.2	30					
300-1500	1	1	f/1500	30					
1500-100,000	/	/	1.0	30					

frequency in MHz

⁼Plane-wave equivalent power density

RF exposure compliance will need to be determined with respect to 1.1307(c) and (d) of the FCC rules. The emissions should be within the limits at 300kHz in Table 1 of 1.1310(use the 300kHz limits for 150kHz:614V/m,1.63A/m).

3 Test Setup



4 Test Procedure

- 1) The RF exposure test was performed in anechoic chamber.
- 2) The measurement probe was placed at test distance (15 cm from all sides and 20 cm from the top) which is between the edge of the charger and the geometric center of probe.
- 3) The highest emission level was recorded and compared with limit as soon as measurement of each points (A, B, C, D, E) were completed.
- 4) The EUT was measured according to the dictates of KDB 680106 D01v03.

Remark: The EUT's test position A, B, C, D and E is valid for the E and H field measurements.

5 Test Instruments list

Test Equipment	Manufacturer	Model No.	SN.	Cal.Date (mm-dd-yy)	Cal.Due date (mm-dd-yy)
Exposure Level Tester	Narda	ELT-400	N-0231	June. 25 2020	June. 24 2021
Magnetic field probe 100cm ²	Narda	ELT probe 100cm ²	M0675	June. 25 2020	June. 24 2021

6 Test Support Equipment list

Equipment	Manufacturer	Model No.	SN.	Remark
Adapter	Salcom	V2323	N/A	N/A
Mobile phone	Huawei	Mate 30	N/A	N/A
Mobile phone	Apple	iphone X	N/A	N/A

Xixiang Road, Baoan District, Shenzhen, Guangdong, China 518102



7 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

• FCC —Registration No.: 381383

Global United Technology Services Co., Ltd., Shenzhen EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in files. Registration 381383.

• IC —Registration No.: 9079A

The 3m Semi-anechoic chamber of Global United Technology Services Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 9079A

• NVLAP (LAB CODE:600179-0)

Global United Technology Services Co., Ltd., is accredited by the National Voluntary Laboratory Accreditation Program (NVLAP). LAB CODE:600179-0

8 Test Result

H-Filed Strength at 15 cm from the edges surrounding the EUT (A/m)

Test Mod e	Unit	Charging Battery Level	Frequenc y Range (MHz)	Test Position A	Test Position B	Test Position C	Test Position D	Test Position E	50% Limits (A/m)	Limits (A/m)
	uT	1%	0.110-0.2	0.30	0.29	0.33	0.19	0.30		
	A/m	1 /0	05	0.24	0.23	0.26	0.15	0.24	0.815	1.63
Mate	uT	50%	0.110-0.2	0.26	0.25	0.30	0.16	0.29		
30	30 A/m	30 70	05	0.21	0.20	0.24	0.13	0.23	0.815	1.63
	uT	99%	0.110-0.2	0.21	0.33	0.28	0.13	0.31		
	A/m	9976	05	0.17	0.26	0.22	0.10	0.25	0.815	1.63
	uT	1%	0.110-0.2	0.23	0.21	0.24	0.19	0.23		
	A/m	1 70	05	0.18	0.17	0.19	0.15	0.18	0.815	1.63
iphon	iphon uT	50%	0.110-0.2	0.20	0.19	0.20	0.16	0.20		
e X	A/m	30 %	05	0.16	0.15	0.16	0.13	0.16	0.815	1.63
	uT	99%	0.110-0.2	0.18	0.18	0.18	0.14	0.20		
	A/m 99%	3370	05	0.14	0.14	0.14	0.11	0.16	0.815	1.63

Note:A/m=uT/1.25



H-Filed Strength at 20 cm from the top of the EUT (A/m)

Test Mode	Unit	Charging Battery Level	Frequency Range (MHz)	Test Position E	50% Limits (A/m)	Limits (A/m)
	uT	1%	0.110-0.205	0.24		
	A/m	1 70	0.110-0.205	0.19	0.815	1.63
Mate 30	uT	50%	0.110-0.205	0.20		
Mate 30	A/m	30 /6	0.110-0.203	0.16	0.815	1.63
	uT	99%	0.110-0.205	0.18	-	
	A/m	99 /0	0.110-0.203	0.14	0.815	1.63
	uT	1%	0.110-0.205	0.21		
	A/m	1 /0	0.110-0.203	0.17	0.815	1.63
iphone X	uT	50%	0.110-0.205	0.18		
ірпопе х	A/m	JU /0	0.110-0.203	0.14	0.815	1.63
	uT	99%	0.110-0.205	0.14	-	-
	A/m	33 /0	0.110-0.203	0.11	0.815	1.63

Note:A/m=uT/1.25

E-Filed Strength at 15 cm from the edges surrounding the EUT (V/m)

Test Mode	Unit	Charging Battery Level	Frequency Range (MHz)	Test Position A	Test Position B	Test Position C	Test Position D	Test Position E	50% Limits (V/m)	Limits (V/m)
N A = C =	V/m	1%	0.110-0.205	90.48	86.71	98.02	56.55	90.48	307.0	614.0
Mate 30	V/m	50%	0.110-0.205	79.17	75.4	90.48	49.01	86.71	307.0	614.0
	V/m	99%	0.110-0.205	64.09	98.02	82.94	37.7	94.25	307.0	614.0
	V/m	1%	0.110-0.205	67.86	64.09	71.63	56.55	67.86	307.0	614.0
iphon e X	V/m	50%	0.110-0.205	60.32	56.55	60.32	49.01	60.32	307.0	614.0
	V/m	99%	0.110-0.205	52.78	52.78	52.78	41.47	60.32	307.0	614.0

Note: V/m= A/m *377

Test Engineer:

Reviewer:

Global United Technology Services Co., Ltd.

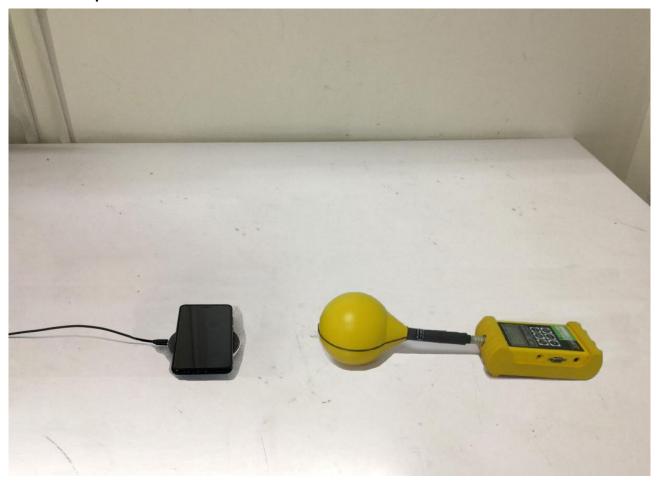
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9 Test Set-up Photo



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